



Oita DRY ArF S307E QC Check Sheet

project			Specification	input
				First time
PSG	Focus (Average)	BestFocus	ÿÿmÿ	0.004
		-Scan		0.004
		+Scan		0.005
		Scan poor		-0.002
		OFFSET		Record only
		Leveling (Angle)	X -Scan	ÿppmÿ
	X +Scan		0.173	
	X Scan Difference		-0.183	
	OFFSET		Record only	-1.050
	Y -Scan		ÿppmÿ	-0.231
	Y +Scan			0.000
	Y Scanÿ			-0.231
	OFFSET		Record only	-1.157
SEFF-PSG	Focus (Average)	-Scan	ÿÿmÿ	0.003
		+Scan		0.003
		Leveling (Angle)	X -Scan	ÿppmÿ
	X +Scan		0.377	
	Y -Scan		-0.242	
	Y +Scan	-0.144		
AIS (Amplification Error)	Lighting conditions	ID 1 Reading	Record only	0.025
		ID 2 Reading		0.008
		ID 21 reading		0.047
		ID 22 reading		0.046
		ID 23 reading		0.007
		ID 24 reading		-0.001
		ID 25 reading		0.048
		ID 31 reading		-0.002
		ID 51 reading		0.015
		ID 101 reading		0.004
		ID 102 reading		0.000
		Each lighting room (Max-Min)		ÿÿmÿ
	AIS image plane	Image tilt	Angle X	ÿÿradÿ
Angle Y			ÿÿradÿ	0.694
Calculated image plane Max-Min		ÿÿmÿ	0.075	
PSD measurement repeatability Each sensor: 3ÿ(n-1) MAX			ÿnmÿ	33.266
AF sensor offset	Max-Min		ÿÿmÿ	-0.042
	Max Sensor Number		Record only	33.000
	Min Sensor Number			8.000
	Max sensor value			0.007
	Min sensor value			-0.035

AIS measurement repeatability			ȳȳmȳ	0.006
Illuminance & Illuminance Unevenness (Static confirmation)	ID 1	Illumination Power	Illumination Power: ȳmWȳcm2ȳ Uniformity:ȳ%ȳ	1038.304
		Uniformity		0.880
	ID 2	Illumination Power		1040.320
		Uniformity		0.805
	ID 21	Illumination Power		977.840
		Uniformity		0.808
	ID 22	Illumination Power		1024.388
		Uniformity		0.828
	ID 23	Illumination Power		1028.824
		Uniformity		0.963
	ID 24	Illumination Power		1129.564
		Uniformity		1.069
	ID 25	Illumination Power		2320.100
		Uniformity		0.964
	ID 31	Illumination Power		1076.280
		Uniformity		0.962
	ID 51	Illumination Power		677.208
		Uniformity		0.559
	ID 99	Uniformity		10.803
	ID 101	Illumination Power		1121.172
		Uniformity		0.851
	ID 102	Illumination Power		1099.160
		Uniformity		0.837
Overlay MODE 1	Offset X	AVE	ȳȳmȳ	-0.006
		TOTAL3ȳ		0.022
		Previous difference		-0.002
		OFFSET		0.190
	Offset Y	AVE		-0.001
		TOTAL3ȳ		0.011
		Previous difference		-0.010
		OFFSET		0.004
Overlay MODE 1 Wafer ingredients	W.Scal X	AVE	ȳppmȳ	-0.001
		Previous difference		-0.016
	W.Scal Y	AVE		0.010
		Previous difference		-0.030
	W.Orth	AVE		-0.031
		Previous difference		0.008
	W.Rot	AVE		0.011
		Previous difference		-0.020
	S.Scal X	AVE		0.125
		Previous difference		-0.109
		OFFSET		0.047
		AVE		0.010

Overlay MODE 1 Shot Ingredients	S.Scal Y	Previous difference	ÿppmÿ	-0.171
		OFFSET		2.195
	Skew	AVE		0.547
		Previous difference		0.091
		OFFSET		-3.374
	S. Rot	AVE		-0.058
		Previous difference		-0.133
		OFFSET		-5.032
Overlay Wafer High-order	Wafer Random	X	ÿnmÿ	7.20
		AND		8.20
Lens Distortion	Worst X		ÿÿmÿ	-0.007
	Worst Y			-0.005
	Differential Worst X		ÿÿmÿ	-0.003
	Worst Y difference			0.004
Stepping	Wafer Random X+Shot Variation		ÿnmÿ	9.1
	Wafer Random Y+Shot Variation			9.9
Mecapri (Input reproducibility)	X	AVE	ÿÿmÿ	9.611
		3p		5.814
	AND	AVE		14.948
		3p		7.380
	I	AVE		13.100
		3p		9.182
Waist flatness (Double-sided polished wafer)	Local Wafer Flatness MAX		ÿÿmÿ	0.235
Synchronization Accuracy	X(Max/Max)	Mean X MAX	ÿnmÿ	5.372
	X(Min/Min)	Mean X MIN	ÿnmÿ	-2.876
	Y(Max/Max)	Mean Y MAX	ÿnmÿ	2.158
	Y(Min/Min)	Mean Y MIN	ÿnmÿ	-3.047
	X(Max/Max) MSD X MAX		ÿnmÿ	11.396
	Y(Max/Max)	MSD Y MAX		15.063
Stage Moving mirror bending	X		ÿnmÿ	4.326
	AND			4.944
COMA Caleb.	Current Result Z7		ÿlÿ	0.003
	Current Result Z8			-0.003
Lens flare check	Eth		Record only	4.40
	E0			400.00
	Flare amount (= ETH ÷ E0 X 100)		%	1.10
Lighting flare confirmation	Lighting system: upper left flare		Record only	0.29
	Lighting system Left center flare			0.44
	Lighting system: Lower left flare			0.49
	Lighting: Nakagami Flare			0.69
	Lighting system Center flare			0.87
	Lighting system: Middle and lower flares			0.69
	Lighting system: upper right flare			0.35

	Lighting system Right center flare		0.42
	Lighting system: Lower right flare		0.39
	Ave	ȳ % ȳ	0.51